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INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)	Docket Number (Optional) <b>TWI-24910</b>	Application Number <b>NEW</b>
	Applicant(s) <b>Alex Salnik et al.</b>	
	Filing Date <b>HEREWITH</b>	Group Art Unit <b>Unknown</b>

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
MAL	*AA	4,579,463	04/01/1986	Rosencwaig et al.	374	57	05/21/1984
	*AB	4,634,290	01/06/1987	Rosencwaig et al.	374	5	11/14/1985
	*AC	4,636,088	01/13/1987	Rosencwaig et al.	374	5	05/21/1984
	*AD	5,978,074	11/02/1999	Opsal et al.	356	72	07/03/1997
	*AE	6,049,220	04/11/2000	Borden et al.	324	765	06/10/1998
	*AF	6,323,951	11/27/2001	Borden et al.	356	502	03/22/1999
MAL	*AG	US 2002/0167326	11/14/2002	Borden et al.	327	752	03/05/2001

## FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

## OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

MAL	AH	J. Opsal et al., "Theory of the Temporal Behavior of Modulated Optical Reflectance in Silicon," <i>Digest of 5th International Topical Meeting of Photoacoustic and Photothermal Phenomena (Heidelberg, Germany)</i> , July 27-30, 1987, pp. coversheet, 103-104.
MAL	AI	J. Opsal et al., "Temporal behavior of modulated optical reflectance in silicon," <i>J. Appl. Phys.</i> , Vol. 61, No. 1, 1 January 1987, pp. 240-248.
MAL	AJ	A. Rosencwaig et al., "Temporal Behavior of Modulated Reflectance Signal in Silicon," from Review of Progress in Quantitative Nondestructive Evaluation, <i>Rev. Progress in QNDE</i> , Vol. 6A (1987), pp. 237-244.
MAL	AK	A. Rosencwaig et al., "Temporal Behavior of Modulated Optical Reflectance in Silicon," Abstract submitted for the March 1986 Meeting of the American Physical Society March 31-April 4, 1986, <i>Bulletin of the American Physical Society</i> 31(3), March 1986, p. 633.
	<del>AL</del>	<del>Excerpt: Thermo Probe 420 User Manual; Theory of Operation; Damage Relaxation (Decay Factor), 1 page in length. (See p. 3 of this Information Disclosure Statement for explanation)</del>
MAL	AM	In re U.S. Patent Application No. 10/387,259, filed March 12, 2003, entitled "Ion Implant Monitoring Through Measurement of Modulated Optical Response," by Alex Salnik et al., 17 pages in length.

Examiner <b>/Michael A. Lyons/</b>	Date Considered <b>05/18/2006</b>
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	